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In addition to larger original papers brief reports will be published of the author's own research work. The report should be set out according to the above guide lines.

The Editorial Board invites the readers to send over any remarks or observations referring to the publications which will appear in the OPTICA APPLICATA. The correspondence of essential importance will be published in a separate column dealing with letters to the Editor.

Review of matter

Application of the diffraction theory, quantum optics, problems in radiation coherence, light sources, holography and its application, scientific photography, methods of image reconstruction, optical application of Fourier transforms, theory of optical systems, criteria of optical image evaluation, optical materials, technology of manufacturing optical elements, aspheric optics, optical properties of solids photo- and radiometry, problems in spectroscopy, non-linear optics, optical data processing, optical measurements, fibre optics, optical instrumentation, interferometry, microscopy, nonvisible optics, automation of optical computing, optoelectronics, colorimetry, optical detectors, ellipsometry and photoelasticity.

Contents

The Influence of Thermal Stress in Glass Disks on the Intensity Distribution in the Diffraction Image of a Point and on the Transfer Function, K. PIETRASZKIEWICZ	107
On the Partially Coherent Near and Far Field Diffraction, M. ZAJĄC	113
Transformations, Multiple Filtering and Associative Processes in Thick Media for Continuous Image Structures, R. GÜTHER and S. KUSCH	121
Probabilistic Model for Shape Errors of Spherical Surfaces in Optical Elements, M. LEŚNIEWSKI	131
The Electronic Microbalance for Atomic Beam Density Measurements, T. DOHNAŁIK, A. MURYN, M. STANKIEWICZ, M. SZYMANOWSKA	135
On Influence of the Triangle Striae on the Strehl Definition of the Aberrational Optical System, F. RATAJCZYK	137
The Effects of Spherical Aberration on an Electron Beam with Gaussian Current Density Distribution, A. MULAK, W. SŁÓWKO . .	141

Содержание

Влияние температурных напряжений в стеклянных дисках на распределение интенсивности в дифракционном изображении точки и передаточную функцию, К. Петрашкевич	107
О частично когерентной дифракции близкого и далекого полей, М. Заёнц	113
Трансформации, многократное фильтрование и ассоциативные процессы в плотных средах для сплошных структур изображений, Р. Гитер, С. Куш	121
Вероятностная модель для погрешностей формы сферических поверхностей оптических элементов, М. Лесьневски	131
Электронные микровесы для измерения плотности атомной частицы, Т. Дохналик, А. Мурын, М. Станкевич, М. Шынановска	135
Влияние треугольных полос на светлоту Штреля aberrационных оптических систем, Ф. Ратайчик	137
Влияние сферической aberrации на электронный пучок с гауссовым распределением плотноститока, А. Мулак, В. Слувко . .	141

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